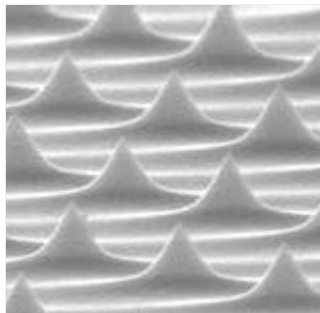


Product Description

Calibration grating TGT1 is intended for

- tip shape and sharpness estimation and further using in deconvolution program;
- tip degradation and contamination control.



SEM image of TGT1 grating

General Features

Structure	the grating is formed on Si wafer top surface
Pattern type	3-D array of sharp tips
Period	$3 \pm 0,05 \mu\text{m}$
Height	$0.3 - 0.5 \mu\text{m}$
Chip size	$5 \times 5 \times 0,5 \text{ mm}$
Effective area	central square $2 \times 2 \text{ mm}$
Tip angle	50 ± 10 degrees (on the very tip end)
Tip curvature radius	$\leq 10 \text{ nm}$
Diagonal period	$2,12 \mu\text{m}$